INFORMATION DISCLOSURE CITATION IN AN APPLICATION					ATTY. DOCKET NO. 50099-238	l	SERIAL NO. Divisi nal f Appl. N 09/988,593			
					APPLICANT Shigenobu MAEDA, et al.					
(PTO-1449)					FILING DATE December 31, 2003 GROUP 2823			3		
				U.S. PATEN	T DOCUMENTS				1 : 3	
EXAMINER'S INITIALS	CITE NO.	Document Number Number-Kind Codez (7 known)		Publication Date MM-DD-YYYY	Name of Patentee or Appli Document		Pages, Columns, Lines, Where Relevant Passages or Relevant Figures Appear			
WP		US	6,410,369	06/2002	Flaker et al.	Flaker et al.				
TNP		US	6,483,165	11/2002	Ooishi et al.			-		
wo		US	U.S.S.N. 09/466,934	12/20/1999	Yamagneti et al.		114	Allowance 11/21/02		
TWP	L	US	U.S.S.N. 09/639,953	08/17/2000	Twamatin +	Twamatin et al.		US 6,495 898		
TUP		US U.S.S.N. 09/677,881		10/03/2000	Matsumoto et al.			US 6,455,894		
	ļ	US								
	{	US								
		US								
	-	US								
4., J.,	,			FOREIGN PAT	ENT DOCUMENTS					
EXAMINER'S INITIALS	CITE NO.	Foreign Patent Document Country Codes -Number « -Kind Codes (# known)		Publication Date MM-DD-YYYY	Name of Patentee or Applicant of Cited Document	Pages, C Where	clumns, Lines Refevant es Appear	evant		
								Yes No		
***							•			
100										
		╁	<u></u> :					ļ		
	-	┼				 		<u> </u>	 	
Eastern Co	11 G (20)	9 60	OTHER A	RT (Including Autho	r. Title: Date. Pertinent Pages F	te)	·	<u>. </u>	<u> </u>	
EXAMINER'S INITIALS	CITE NO.	OTHER ART (Including Author, Title, Date, Pertinent Pages, Etc.) Include name of the author (in CAPITAL LETTERS), title of the article (when appropriate), title of the item (book, magazine, journal, serial, symposium, catalog, etc.), date, page(s), volume-issue number(s), publisher, city and/or country where published.								
WP		Hirano, et al., "Bulk-Layout-Compatible 0.18 µm SOI-COS Technology Using Body-Fixed Partial Trench Isolation (PTI)" Proceedings of 1999 IEEE International SOI Conference, October 1999, pages, 131 – 132								
Twr		Isola	Maeda, et al., "Analysis of Delay Time Instability According to the Operating Frequency in Field Shield Isolated SOI Circuits" Proceeding of IEEE Transactions of Electron Devices, Vol. 45, No.7, July 1998, pages 1479 - 1486							
	 	 								
	L	L	A. III. ISO			···				
ph	am		AMINER		,	DATE CON	ISIDERED			

*EXAMINER: Initial if reference considered, whether or not citation is in conformance with MPEP 609. Draw line through citation if not in conformance and not considered. Include copy of this form with next communication to applicant.

1 Applicant's unique citation designation number (optional). 2 Applicant is to place a check mark here if English language Translation is attached.